Form PTO 1449 (Modified)		U.S. DEPARTMENT PATENT AND TRA	F OF COMMERCE ADEMARK OFFICE	ATTY DOCKET NO. 263468US6PCT		SERIAL NO. 10/522,752			
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LIST OF	REFE'	RENCES CITED BY AF	PPLICANT	Makoto URUSHIHARA, et al.					
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U.S. PATENT DOCUMENTS									
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	AO	JP 3-161826	7-11-1991	Japan (w/English Abstract)				×	
	AP	JP 11-298850	10-29-1999	Japan (with English Abstract and Unedit Computer-Generated English Translatio	on)	×			
	AQ	JP 2000-59731	2-25-2000	Japan (submitting English Abstract and Computer-Generated English Translatio reference previously filed on 2-1-2005)	on only,	x			
	AR	JP 2001-128126	5-11-2001	Japan (with English Abstract and Unedit Computer-Generated English Translatio	on)	x			
	AS	JP 10-214456	8-11-1998	Japan (with English Abstract and Unedit Computer-Generated English Translatio		×			
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		OTHER R	EFERENCES (	Including Author, Title, Date, Pertinent	Pages, e	tc.)			
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conformance and not considered. Include copy of this form with next communication to applicant.									